

Supplementary Information

Large-Scale Nanotwins in Copper Films/Cu Nanowires via Stress Engineering by High Energy Ion Beam Bombardment Process: Growth and Characterization

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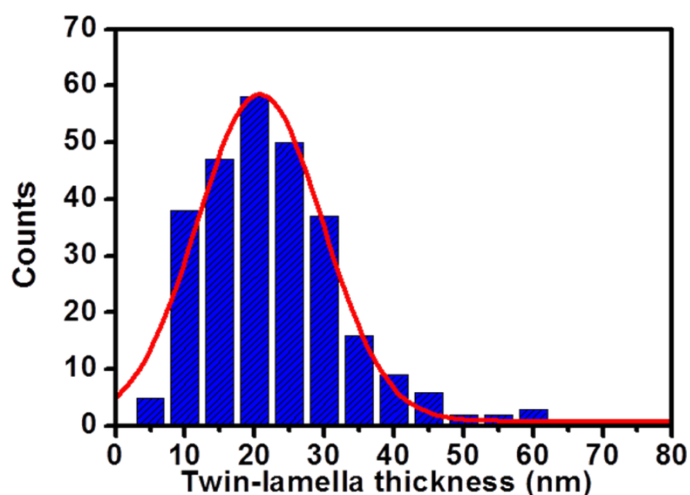


Figure S1 Statistics of twin lamella width distributions for the patterned Cu strips.